

Anloy Technologies Tier Selection Sheet

Tier 0

Processing: Anomaly Inspection
Die extraction for identification

Tier 1

Processing: Anomaly Inspection
Die extraction for identification
25°C Limited DC / Limited Functional Testing

Tier 3

Processing: Anomaly Inspection
Die extraction for identification.
25°C Datasheet DC/AC testing.

Tier 5

Processing: Anomaly Inspection
Die extraction for identification
Datasheet DC/AC testing per below temperature range selection.
Options: 5C=0,25,70 / 5I=-40,25,85 / 5M=-55,25,125

Tier ASx

Processing: As Defined Per 6081
A2, General/Detailed Visual Inspection, 122 devices
A3, Remarking/Resurfacing, 3 devices
A4, Xray Inspection, 45 devices
A5, XRF for Pb content, 3 devices
A6, Delid/Internal Analysis, 3 devices

Replace the "x" with the applicable Test option as below if required.
C1 = 25°C Limited DC / Limited Functional Testing
C3 = 25°C Datasheet DC/AC testing.
C5 = Datasheet DC/AC testing per below temperature range selection.
Options: 5C=0,25,70 / 5I=-40,25,85 / 5M=-55,25,125

Tier X

Processing: Customer Defined Requirements

Add On Options

X-Ray Inspection
XRF for Lead content
Solderability, MIL-STD-883 Method 2002/J-STD-002
Solderability, Commercial Dip and Look (No Preconditioning)
Resistance to Solvents, MIL-STD-883 Method 2015
Remarking/Resurfacing via Heated Chemical Test (HCT)
Burn In Processing

- Notes:**
- Anomaly inspection is defined as external inspection for non-typical original manufacturer practices.
 - Die mask verification is not guaranteed due to the possibility of no die mask information, and or lack of support required from the original manufacturer.
 - Electrical Test Sample size is typically 100pcs unless otherwise defined.
 - Tier 2 and Tier 4 do exist although they are the same but do not include the AC measurements of Tier 3 and Tier 5 respectively.
 - A traceable reference sample is opened at no additional charge for comparison purposes when die results are inconclusive.